

PRODUCT/PROCESS CHANGE NOTICE (PCN)

PCN #: A1709-04	DATE: 25-Oct-2017	MEANS OF DISTINGUISHING CHANGED DEVICES:			
Product Affected: VFQFPN-28 (Refer to Attachment II for the	affected part numbers)	 Product Mark Back Mark Date Code Other Lot # will have: "RC" prefix for ASECL, Taiwan 			
Date Effective: 25-Jan-2018					
Contact: IDT PCN DESK		Attachment: Yes No			
E-mail: pcndesk@idt.com		Samples: Please contact your local sales representative for sample request.			
DESCRIPTION AND PURPOSE OF C	HANGE:				
 Die Technology Wafer Fabrication Process Assembly Process Equipment 					
□ Material	There is no change to the moisture performance.				
 Testing Manufacturing Site Data Sheet Other 	Attachment I details the qualification results.				
RELIABILITY/QUALIFICATION SU Refer to qualification data shown in Atta					
CUSTOMER ACKNOWLEDGMENT	OF RECEIPT:				
IDT records indicate that you require written notification of this change. Please use the acknowledgement below or E-Mail to grant approval or request additional information. If IDT does not receive acknowledgement within 30 days of this notice it will be assumed that this change is acceptable. IDT reserves the right to ship either version manufactured after the process change effective date until the inventory on the earlier version has been depleted.					
Customer:	C	Approval for shipments prior to effective date.			
Name/Date:	E-	Mail Address:			
Title:	Pl	none# /Fax# :			
CUSTOMER COMMENTS:					
IDT ACKNOWLEDGMENT OF REC	EIPT:				
RECD. BY:		DATE:			



Integrated Device Technology, Inc. 6024 Silver Creek Valley Road, San Jose, CA - 95138

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ATTACHMENT I - PCN # : A1709-04

PCN Type:	Manufacturing Site - Alternate Assembly Location		
Data Sheet Change:	None		
	No change in moisture sensitivity level (MSL)		

Detail Of Change:

This notification is to advise our customers that IDT is adding ASECL, Taiwan as an alternate assembly facility for parts that are currently assembled at UTL, Thailand.

The material set details of the current and alternate assembly location is as shown in Table 1.

There is no change to the moisture performance.

Table 1: Assembly Material Sets for The Existing and Alternate Assembly Location

	Existing Assembly (UTL, Thailand)	Alternate Assembly (ASECL, Taiwan)
Die Attach	8600	EN4900G
Bond Wire	Copper Wire	Copper Wire
Mold Compound	G700LTD	G700LA



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Qualification Information and Qualification Data:

- Affected Packages: VFQFPN-28
- Assembly Material: Shown on page 2 of this attachment.

Qual Plan & Results: Tests are in accordance with JEDEC47 recommended tests.

Qualification Vehicle: VFQFPN-36

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Test Description	Test Method	Test Results (Rej / SS)		
Test Description	Test Method	Lot 1	Lot 2	Lot 3
* Temperature Cycling (-55°C to 125°C, 700 cycles)	JESD22-A104	0/25	0/25	0/25
* HAST - biased (130 °C/85% RH, 96 Hrs)	JESD22-A110	0/25	0/25	0/25
High Temperature Storage Bake (150°C, 1000 Hrs)	JESD22-A103	0/25	0/25	0/25
Ball Shear Test	JESD22-B116	0/5	0/5	0/5
Bond Pull Test	MIL-STD-883 (Method 2011)	0/5	0/5	0/5
X Ray	IDT Spec. MAC- 3012	0/45	0/45	0/45
Moisture Sensitivity Level, MSL	J-STD-20 / MSL 1, 260 °C	0/25	0/25	0/25

Tests were subjected to Preconditioning per JESD22-A113 prior to stress test



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ATTACHMENT II - PCN # : A1709-04

Part Number	Part Number	Part Number	Part Number
F1451NKGI	F1456NKGI	F1455NKGI8	F1451NKGK
F1456NKGK	F1455NKGK8	F1455NKGI	F1451NKGI8
F1456NKGI8	F1455NKGK	F1451NKGK8	F1456NKGK8